Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination CHIU ET AL. | Examiner | Art Unit | Prabodh M. Dharia | 2629 | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,030,862	04-2006	Nozaki, Tetsuya	345/173
*	В	US-6,850,229	02-2005	Casebolt et al.	345/173
*	С	US-6,642,857	11-2003	Schediwy et al.	341/20
*	D	US-6,417,846	07-2002	Lee, Si-Ken	345/173
*	Е	US-2004/0021691	02-2004	Dostie et al.	345/773
*	F	US-2003/0069931	04-2003	Omura et al.	709/205
*	G	US-6,088,022	07-2000	Rakoski, Robert Charles	345/168
*	Н	US-2004/0119700	06-2004	Ichikawa, Fumiko	345/173
*	ı	US-2005/0001821	01-2005	Low, Tse How	345/169
*	J	US-2005/0129199	06-2005	Abe, Naoya	379/090.01
*	К	US-2003/0006975 A1	01-2003	Moriya et al.	345/179
*	L	US-6,002,389	12-1999	Kasser, Bernard	345/173
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	\ \	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.